

Daniel Guggenheim School of Aerospace Engineering



Tests and Interpretation of Small Fatigue Crack Growth in Metallic Rotorcraft Structures with Emphasis on the Statistical Characteristics

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Participants



Faculty

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GRA's

- •Marcus Cappelli (Presidents Scholar, PhD student)
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<u>Undergraduate Honors Program</u> <u>Assistants</u>

• Christopher Neglia



Topics



- Summary of Problem
 - Bi- Modal cluster cracking

- Previous Research
 - Scatter in small fatigue crack growth from micro-notches.
- Current Research
 - Data
 - Summary of issues involved in small fatigue crack growth from smooth surfaces.
 - Analysis



Background



- Features of small crack growth
 - Growth-arrest
 - Coalescence of microcracks
 - Growth at <u>smaller SIFs</u> and at <u>faster rates</u> than equivalent long cracks
 - Scatter significantly greater than that for long cracks



Causes of Scatter



- Each small crack front will encounter <u>randomly</u> <u>oriented microstructure</u> and thus have a unique growth pattern.
- Different material forms will have varying grain profiles.
 - Ex. Grains in stock rod will be thin and elongated while those in plate are characterized by three dimensions; longitudinal, transverse and short transverse.
- Randomly arranged crack cluster neighborhoods affect growth through shielding and coalescence.



Smooth Surface Current Research



- On smooth surfaces the onset of cracking occurs in randomly arranged clusters described as micro-multisite cracking.
- Many cracks will arrest (effectively non-propagating cracks), secondary.
- Propagating (primary) cracks are those that continue to grow, possibly through crack coalescence and can ultimately lead to failure.
- Primary cracks are influenced by the shielding effects of the network of nearby secondary cracks which create a unique environment for growth.



Bi-Modal Crack Distributions



- Small Crack distributions are bi-modal: Both primary and non-propagating cracks have separate distributions.
- First noticed by Swain who termed Valid and Invalid cracks while looking for which cracks to include in studies.
- Distributions cannot be separated in early stages of loading.
 - Measurements are started once cracks are of a detectable size.
 - Tests are stopped at regular intervals and cracks/clusters are measured and recorded.
 - Tests are run until failure.
 - Based on long crack data the distributions can be separated.



Micro-Notches Past Research



• Test Setup

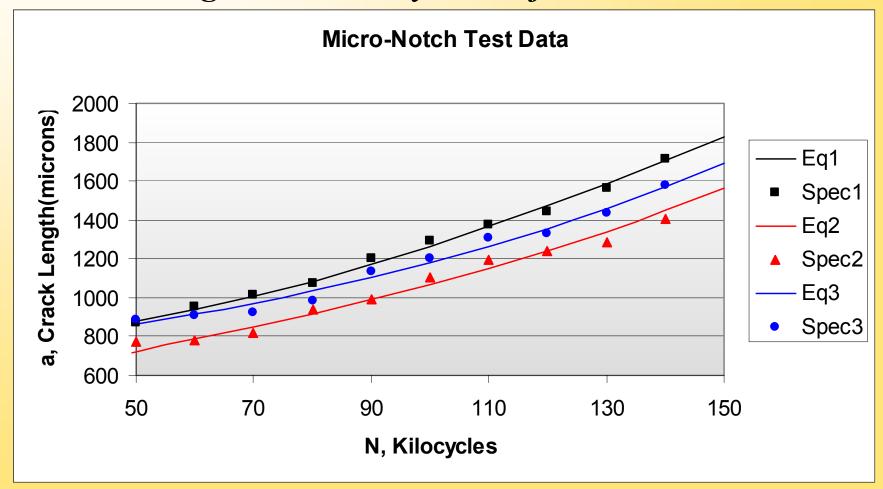
- Alloy: 6061-T651 (rod form)
- Grain size: Transverse -200 microns,
 Longitudinal 350 microns
- Properties: 0.2% offset yield stress 283 MPA,
 ultimate strength 293 MPA
- Test specimen: Square cross-section150 micron notch corner edge
- Loading condition: Bending about a cross section diagonal
- Maximum stress of 0.8 yield stress on corner edge
- Loading frequency: 10Hz



Test Data



Cubic Regression Analysis Performed on Data

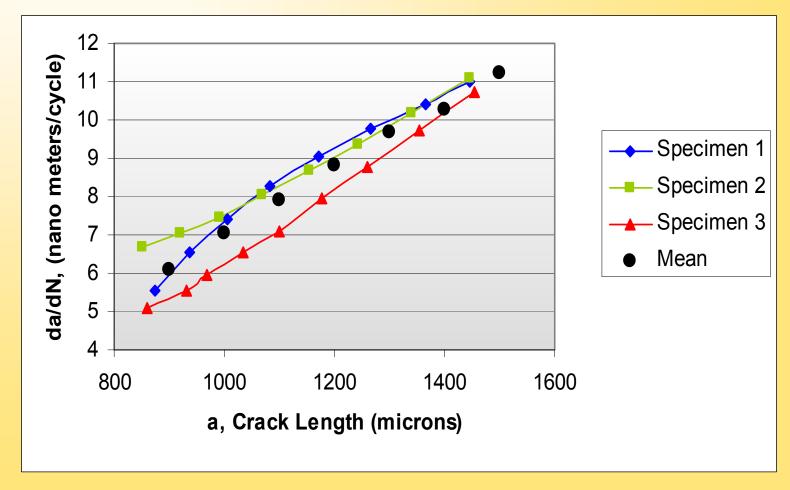




Regression Analysis



• da/dN computed by differentiating resulting equations





Trends in Standard Deviation



• Behavior of <u>S.D. of crack growth rates</u> can be represented by exponential function of the form:

$$S = Ce^{B\Phi(a)}$$

- $a = crack\ length,\ C,B = Constants$
- Nonlinear regression analysis provides the following:

$$S = 0.81e^{\left[-2.299 \cdot 10^{-6} (a - 800)^{2}\right]}$$



Grain Intersection Analysis

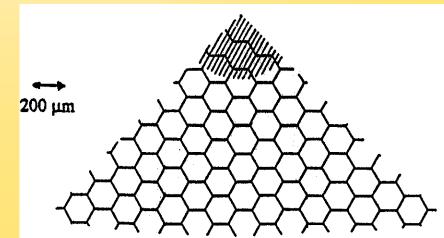


• Corner Crack fronts assumed to grow with quarter circular crack fronts.

$$n = \frac{1}{2}\pi \left(\frac{a}{d}\right)$$

• n = number of grains intersected by crack front a = Crack depth

d = Mean grain diameter

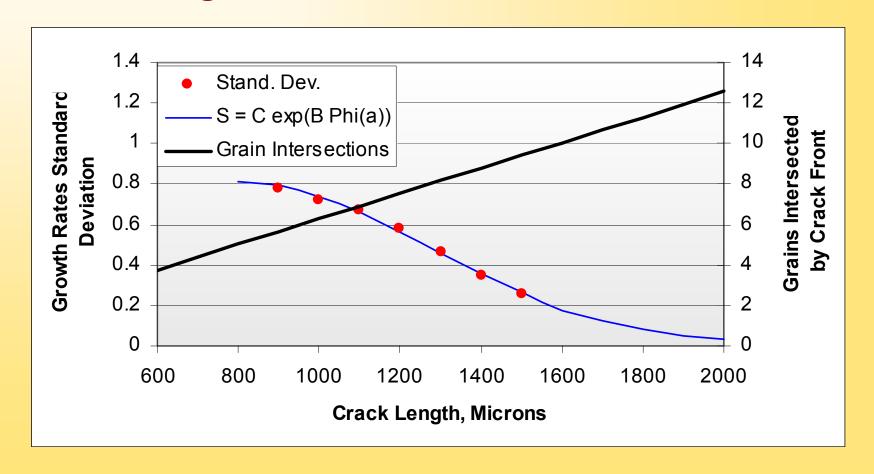




S.D. and Grain Intersection Relations



Grain Intersections and Standard Deviation Vs.
 Crack Length





Grain Intersection Relations



- Number of grains intersected by crack front is a linear function of the crack length.
- S.D. can therefore be expressed as a function of number of intersections:

$$S = Ce^{B\Theta(n)}$$

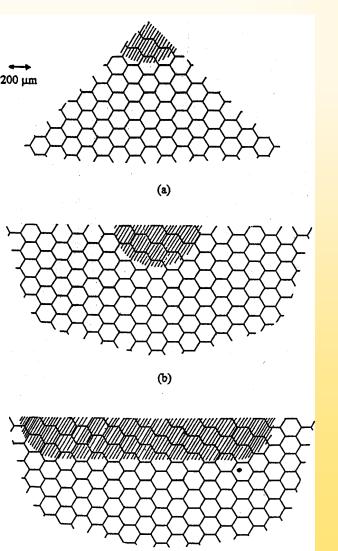
- Applications to multiple crack shapes
 - Ex. Thumbnail cracks intersect twice as many grains as similar depth corner cracks.

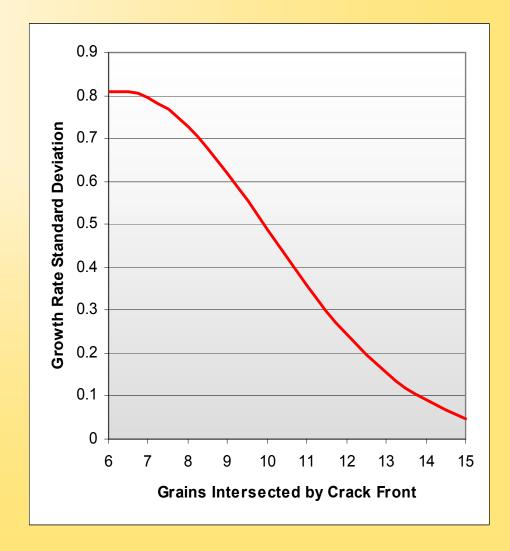


Grain Intersection Relations



• S.D. in Growth Rate vs. Grain Intersections







Georgia Distribution Separation Tech



- Primary cracks are those that have reached long crack size by failure.
- Cracks assumed to be semi-circular and be long after 14 grain intersections.

$$n = \frac{1}{2}\pi \left(\frac{a}{d}\right), \ d = .00145in \ (long./short \ tran.)$$

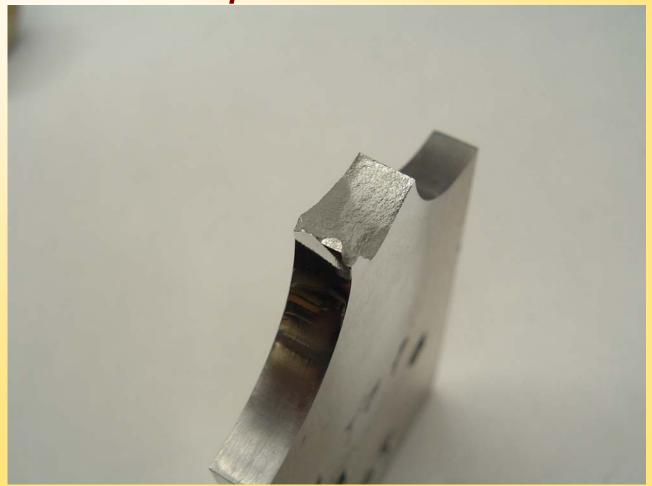
- Semi-circular assumption backed up by failed specimen observations.
- Borderline cracks are separated by observing crack growth rates.



Distribution Separation



• Failed specimens often reveal additional cracks that did not lead to specimen failure.





Test Procedure



- Sinusoidal Loading
- Loading Frequency: 20 Hz
- R = .1, Max Load 5000 Lbs

- Max Load approx. 75% σ_{yield}
- Measurements taken on Questar Telemicroscope.

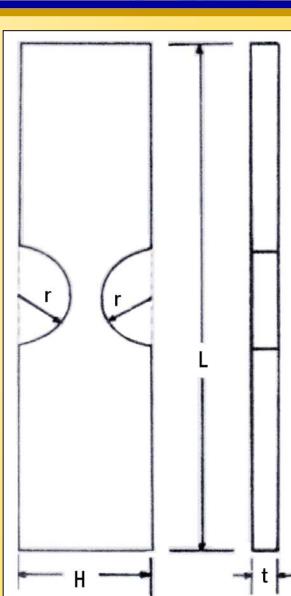




Test Specimen



- L = 8 in, H = 2 in
- t = 0.25 in, r = 0.75 in
- SCF = 1.2 (over ligament stress)
- Mid-Section Polished with:
 - Three abrasive papers
 - · 240, 320, 600
 - Three Diamond Pastes
 - 15, 6, 1μ (applied with low nap cloth)



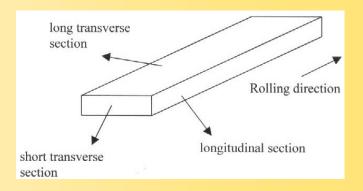


Material Properties



Aluminum 7075-T7351

- Material Properties:
 - Mean σ_{vield} = 64.0 ksi
 - Mean σ_{Ult} = 75.3 ksi



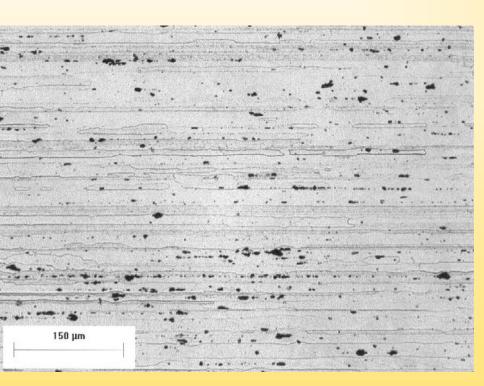
- 1/4 inch plate material with pancake grain structure.
- Mean linear intercept grain dimensions:
 - 58.8 microns (Longitudinal)
 - 76.1 microns (Transverse)
 - 15.0 microns (Short Transverse)

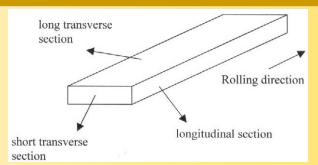


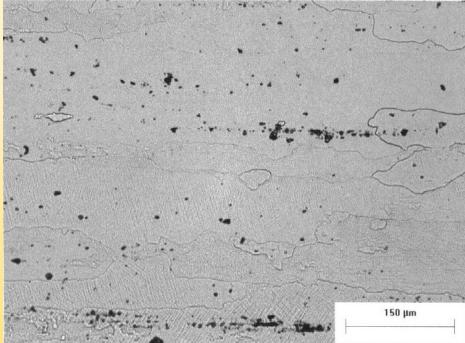
Material Properties



•Sample of material etched with Kellers reagent







Longitudinal

Short Transverse



Raw Data Sample

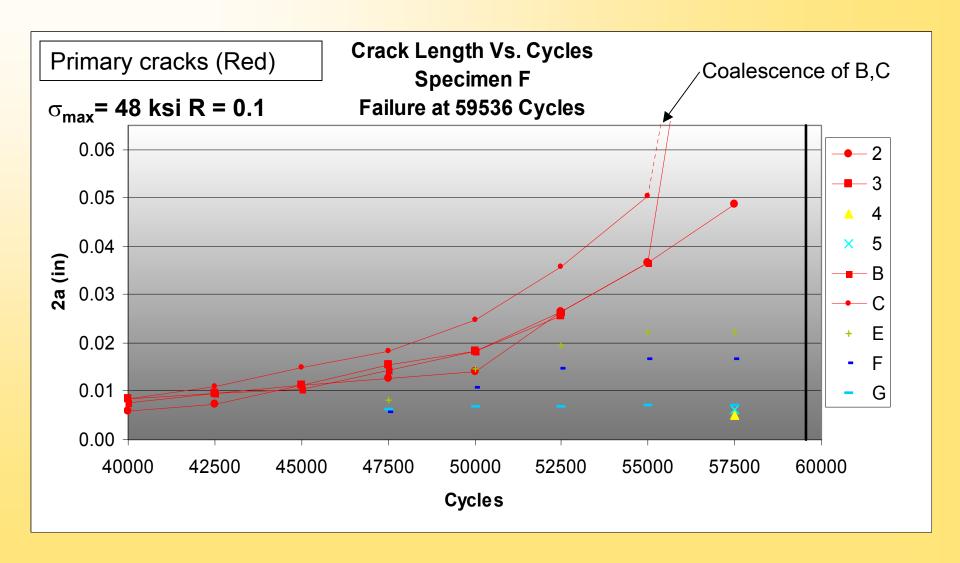


						Stepped C	rack,		
men C 60294 Cycles to Failure			Coalescence, additional data						
	40000	42500	45000	47500	▲ 5 0000	52500	55000	57500	60000
			Distribution:	Primary					
Side 2									
		-0.04985	-0.04955	-0.10320	-0.10190	-0.10630	-0.10640	-0.10470	-0.10285
		0.15770	0.15445	0.15375	0.15510	0.14985	0.14445	0.14735	0.13725
		0.16260	0.16305	0.16405	0.16760	0.16605	0.17120	0.18615	0.19745
		0.00490	0.00860	0.01030	0.01250	0.01620	0.02675	0.03880	0.06020
		0.00000148	0.00000108	7.8E-07	0.00000118	0.00000285	0.00000452	0.00000669	8.56E-06
			Distribution:	Primary					
Side 2				-					
				0.06965	0.07140	0.06665	0.06680	0.06780	0.06890
				0.09030	0.08875	0.08415	0.07900	0.08765	0.08430
				0.09595	0.09845	0.09530	0.09460	0.10455	0.10775
				0.00565	0.00970	0.01115	0.01560	0.01690	0.02345
				0.00000162	0.0000011	0.00000118	0.00000115	0.00000157	0.00000262
Locati	on Cod	rdinatos							
LUCati	on Coc	Juliales	Distribution:	Secondary					
Side 2									
					0.00620	0.00165	0.00135	0.00285	0.00415
					0.07810	0.07415	0.07065	0.07675	0.07655
					0.08470	0.08250	0.08100	0.09120	0.09240
					0.00660	0.00835	0.01035	0.01445	0.01585
					7E-07	7.5E-07	0.00000122	0.0000011	5.6E-07
					— Coalesced with A				
			Distribution:	Secondary	Joane	Jose Hill F			
Side 2				,					
						-0.10845			
						0.16805			
						0.17285			
						0.00480			
	Side 2 Side 2 Locati	Side 2 Side 2 Location Coc Side 2	A0000 A2500	### ### ##############################	## A0000 ## A2500 ## A2500	A0000 A2500 A5000 A7500 Distribution: Primary	Coalescent Coa	A0000 A2500 A5000 A7500 A750	Coalescence, additional data Coalescence, additional data



Crack Measurement Data



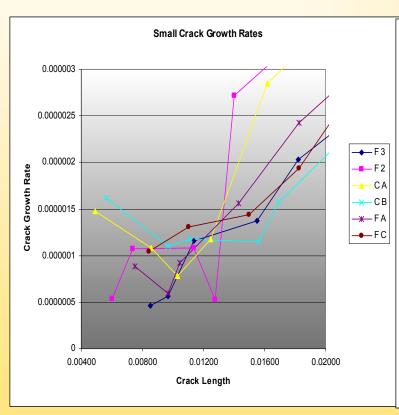


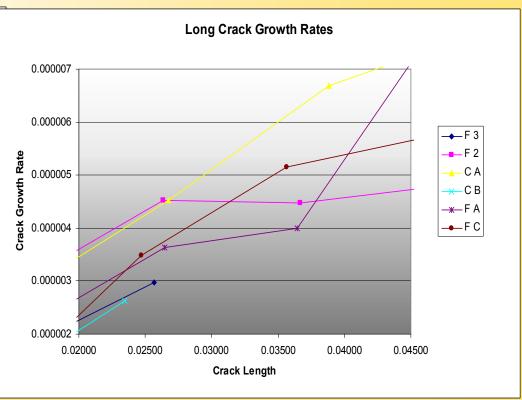


Crack Growth Rate Data



Growth Rates of Primary Cracks



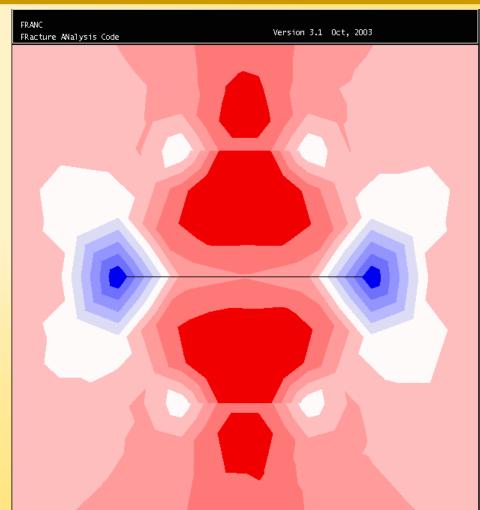




Illustrative Crack Shielding FEM







 K_I =1.872, 1.455

 $K_I = 1.913, .7129$



Evolution of Clusters



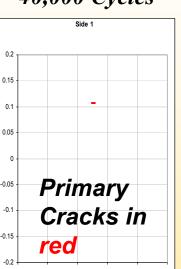
40,000 Cycles

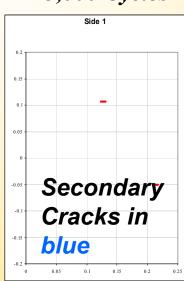
45,000 Cycles

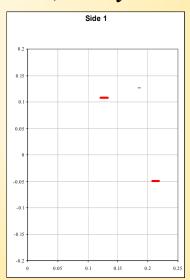
50,000 Cycles

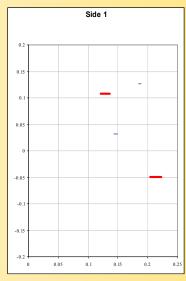
55,000 Cycles

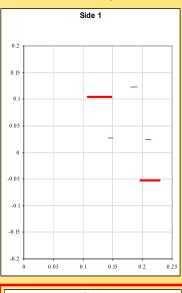
60,000 Cycles

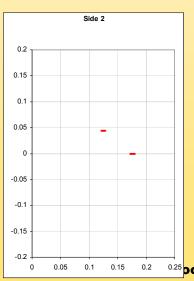


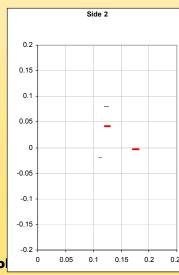


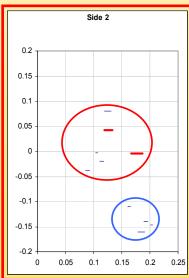


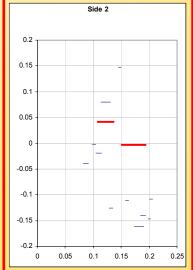


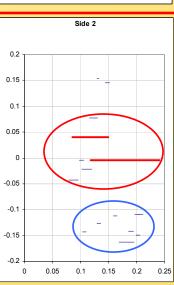










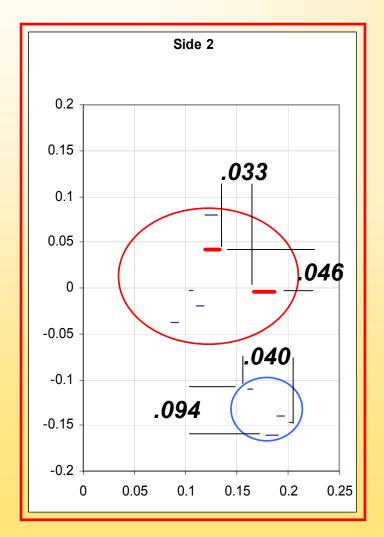




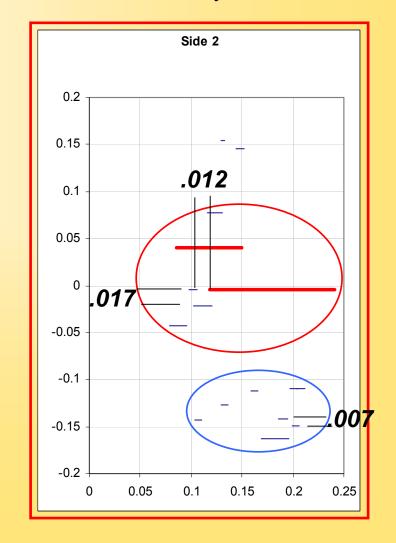
Evolution of Clusters



50,000 Cycles



60,000 Cycles



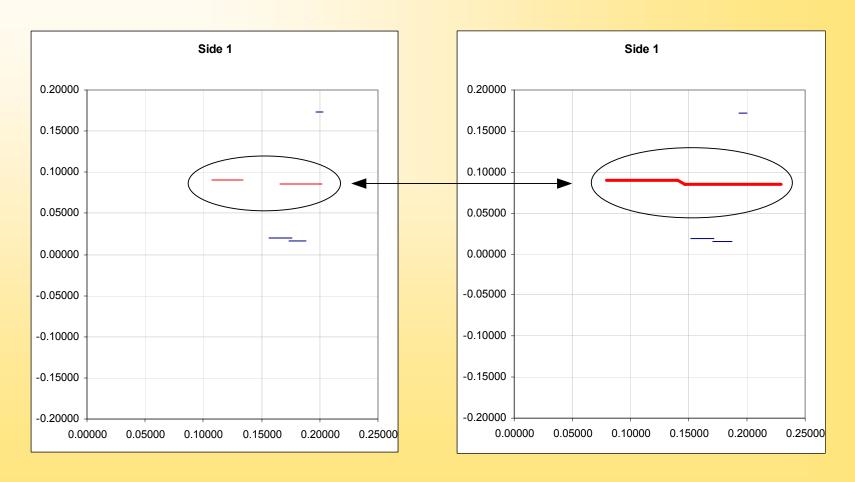


Evolution of Clusters



52,500 Cycles

57,500 Cycles

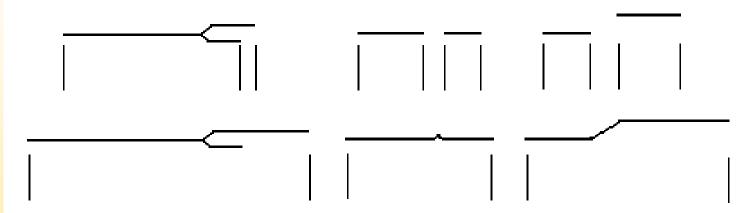




Crack Morphology



Examples of Observed Crack Patterns



- •Many cracks will have complex shapes
- Long crack behavior must be observed to assign proper length





Crack Morphology



Examples of Observed Crack Patterns

Name	Stage 1	Stage 2	Explanation	
Forked Crack	<u></u>		One fork arrests, one grows.Length is length to longer fork.	
Kinked Crack			 Formed through coalescence. Tabulated as one crack after coalescence. 	
Stepped Crack			 Formed through coalescence, which does not always occur. Tabulated as one crack after coalescence. 	



Analysis



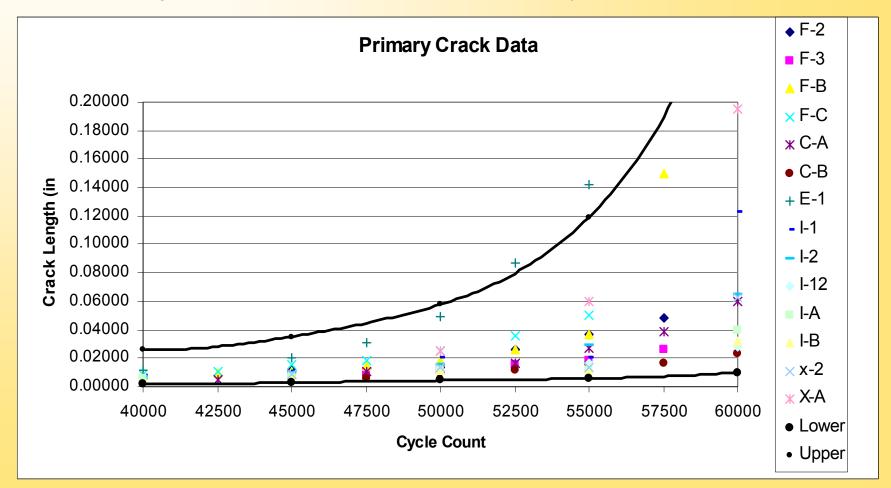
- Lognormal distribution assumed for crack lengths at each cycle count.
- Student-t analysis performed to calculate 95% confidence bounds.
- This procedure can be used to bound small crack growth until a_{cr}, where normal methods of crack growth analysis can be used.
- This allows calculation of the 95% confidence limit on failure time.



Analysis Example



Confidence Bounds on Primary Crack Growth





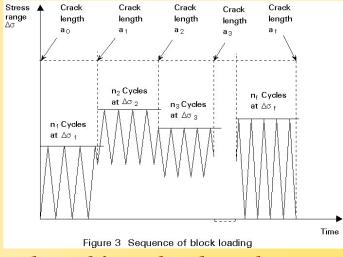


- Extend the Bi-Modal statistical representation of small cracks.
- Similar to EIFS methodology however it seeks a physically based approach to include the entire small crack regime.
- Issues to be resolved:
 - Stress level/Load ratio (R) effects.





• Operational Condition Issues



- Variable amplitude loading, overload/underload effects.
- Material orientation effects (ex. Plate, rod...)
- Surface preparation effects.





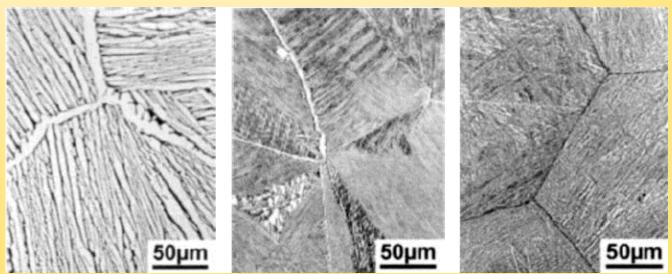
- Analysis:
 - Crack shielding in random cluster effects.

Use of statistically based, effective stress intensity factor incorporating above mentioned physical effects.





- Additional Materials (\(\beta\text{-Annealed Ti-6Al-4V}\):
 - Dual Phase, Widmänsatten/Colony Microstructure
 α (HCP), β (BCC)
 - Key Parameters: Prior β grain size, α Colony Size,
 Width of α Lamellae





Contact Information/ Questions



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Questar



- Questar QM1 Telemicroscope
- $\approx 125 x$ magnification
- Better than 3µ resolution
- Capable of VHS recording



